



Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09550649	GUERTIN ET AL.
	Examiner Kim, David S	Art Unit 2633

Notes	Date	Examiner
EAST search - see search history printout	11/03/2005	DSK, 11/04/06
text search in 714/704-717	11/03/2005	DSK
www.google.com - various combinations of the following terms: wdm dwdm loopback "loop back" cascade chain test sectionalize ber test wavelength channel serial daisy optical testing t-berd 310 bit error tester sections bert		DSK, 11/2006
scholar.google.com - various combinations of the following terms: sectionalize wdm dwdm ber bert test equipment monitor section chain cascade daisy		DSK, 11/2006
EAST search - see search history printout	5/24/2006	DSK
www.google.com - various combinations of the following terms: measure ber q-factor calculate	5/24/2006	DSK
scholar.google.com - various combinations of the following terms: q-factor "q factor" ber monitor tester bert	5/24/2006	DSK
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Class	SubClass	Date	Examiner
398	27	11/03/2005	DSK
714	716	11/03/2005	DSK
398	26, 27	5/24/2006	DSK

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